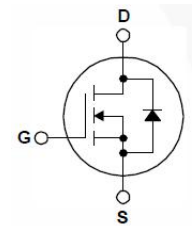
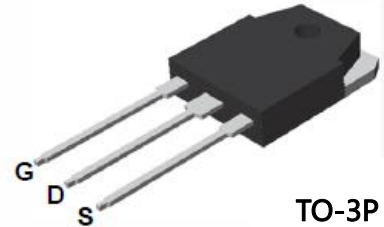


200V N-Channel MOSFET

Features

- $V_{DS}=200V$ $I_D=90A$
- $R_{DS(ON)}=18m\Omega(Typ.)@V_{GS}=10V$
- Low On-Resistance
- Improved dv/dt capability
- Super Low Gate Charge
- 100% EAS Guaranteed
- Fast switching speed

PIN DESCRIPTION



Applications

- High frequency switching mode power supply
- Uninterruptible Power Supply
- Power Factor Correction

Part Number	Package	Marking	ROHS Status	Packing
SI200N06P	TO-3P	SI200N06P	Pd-Free	Box(Tube)

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DS}	Drain-Source Voltage	200	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Continuous Drain Current	$T_c=25^\circ C$ 90	A
I_{DM}	Pulsed Drain Current	360	A
E_{AS}	Single Pulse Avalanche Energy	2113	mJ
I_{AS}	Avalanche Current	54	A
E_{AR}	Repetitive Avalanche Energy	1268	mJ
T_J, T_{stg}	Operating Junction and Storage Temperature Range	-55 to 150	$^\circ C$
P_D	Total Power Dissipation	$T_c=25^\circ C$ 580	W

THERMAL RESISTANCE RATINGS

Symbol	Paramete	Typical	Max	Unit
$R_{\theta JA}$	Maximum Junction-to-Ambient	-	40	$^\circ C/W$
$R_{\theta JC}$	Maximum Junction-to-Case	-	0.26	

Electrical Characteristics (T_C=25°C unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	TYP.	Max.	Unit
Static Characteristics						
V _{(BRV)DSS}	Drain-source breakdown voltage	V _{GS} =0V, I _D = 250uA	200	-	-	V
V _{GS(th)}	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250uA	2	-	4	V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =200V, V _{GS} =0V	-	-	1	uA
I _{GSS}	Gate-source leakage current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
R _{DS(on)}	Drain-source on-state resistance	V _{GS} =10V, I _D =45A	-	18	-	mΩ
Dynamic Characteristic						
Q _g	Total Gate Charge	V _{GS} =10V, V _{DD} =100V I _D =45A	-	400	-	nC
Q _{gs}	Gate-Source Charge		-	25	-	nC
Q _{gd}	Gate-Drain Charge		-	240	-	nC
T _{d(on)}	Turn-on delay time	I _D =45A, V _{DD} =100V, R _G =1.2Ω, V _{GS} =10V	-	75	-	nS
T _r	Rise time		-	325	-	nS
T _{d(off)}	Turn-off delay time		-	1500	-	nS
T _f	Fall time		-	480	-	nS
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =25V f=1.0MHz	-	5700	-	pF
C _{oss}	Output Capacitance		-	1005	-	pF
C _{rss}	Reverse Transfer Capacitance		-	445	-	pF
Source-Drain Diode						
V _{SD}	Diode Forward Voltage	V _{GS} =0V, I _S =45A	-	-	1.4	V
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	360	A
I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	90	A
T _{rr}	Reverse Recovery Time	V _{GS} =0V, I _F =45A, diF/dt=100A/μs	-	250	-	ns
Q _{rr}	Reverse Recovery Charge		-	275	-	uC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 2% .
3. L=1mH, V_{DD}=50V, R_G=25 Ω, Starting T_J = 25 °C .

Typical Characteristics (T_J = 25°C, unless otherwise noted)

Figure 1. Output Characteristics (T_J = 25°C)

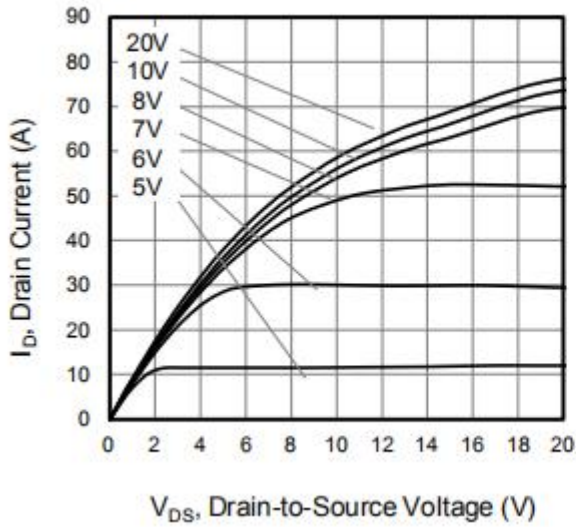


Figure 2. Body Diode Forward Voltage

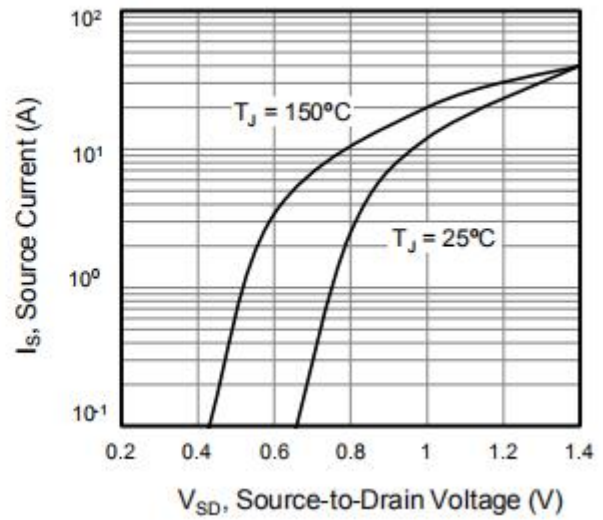


Figure 3. Drain Current vs. Temperature

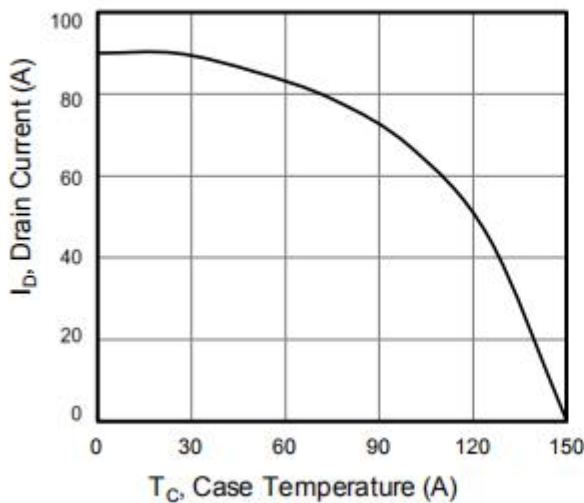


Figure 4. BV_{DSS} Variation vs. Temperature

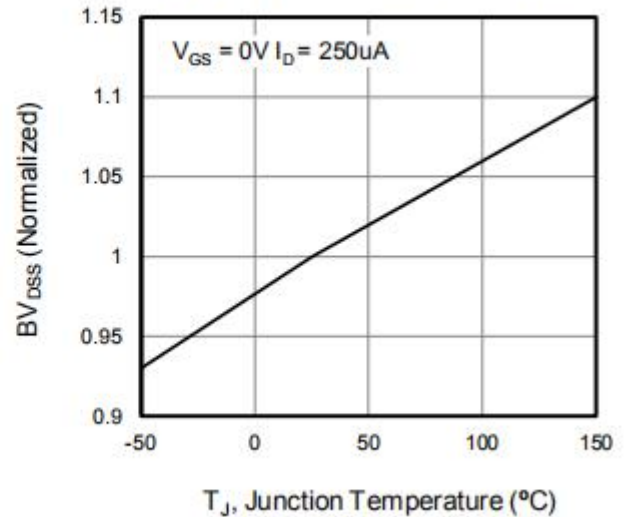


Figure 5. Transfer Characteristics

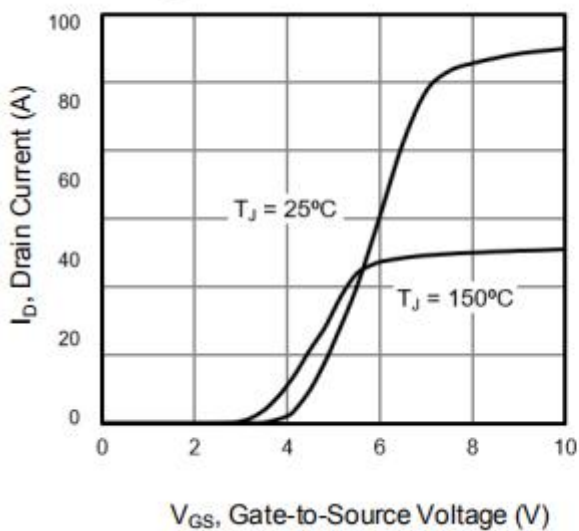
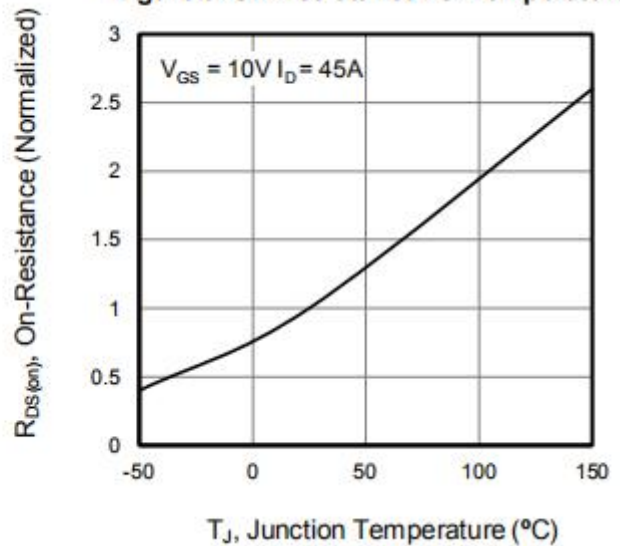


Figure 6. On-Resistance vs. Temperature



■ Switching Time Test Circuit and Wave forms

Figure A: Gate Charge Test Circuit and Waveform

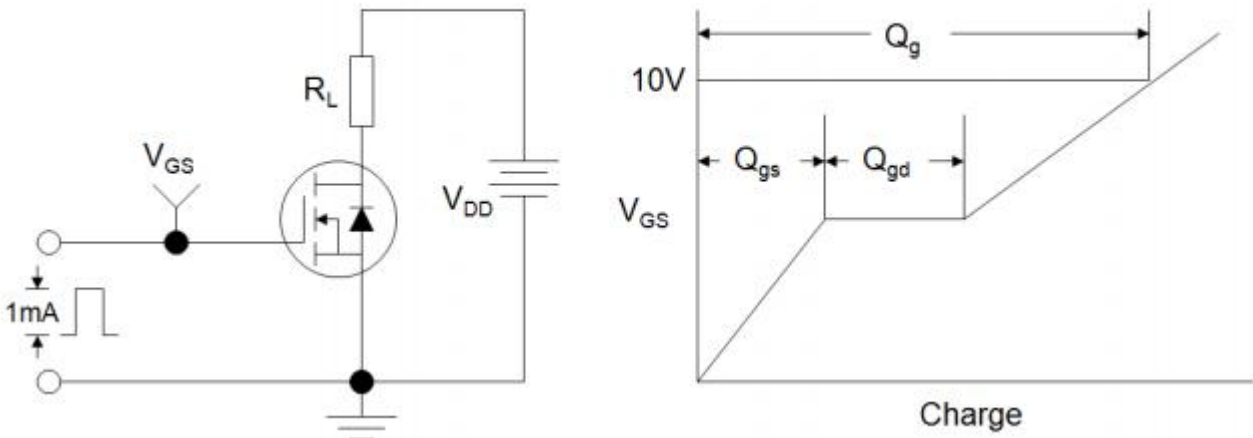


Figure B: Resistive Switching Test Circuit and Waveform

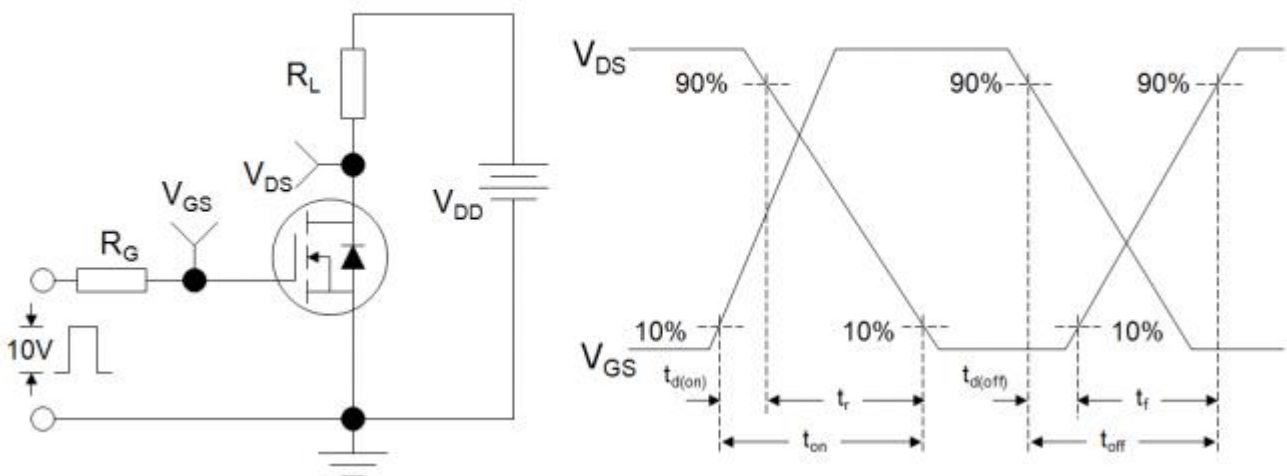
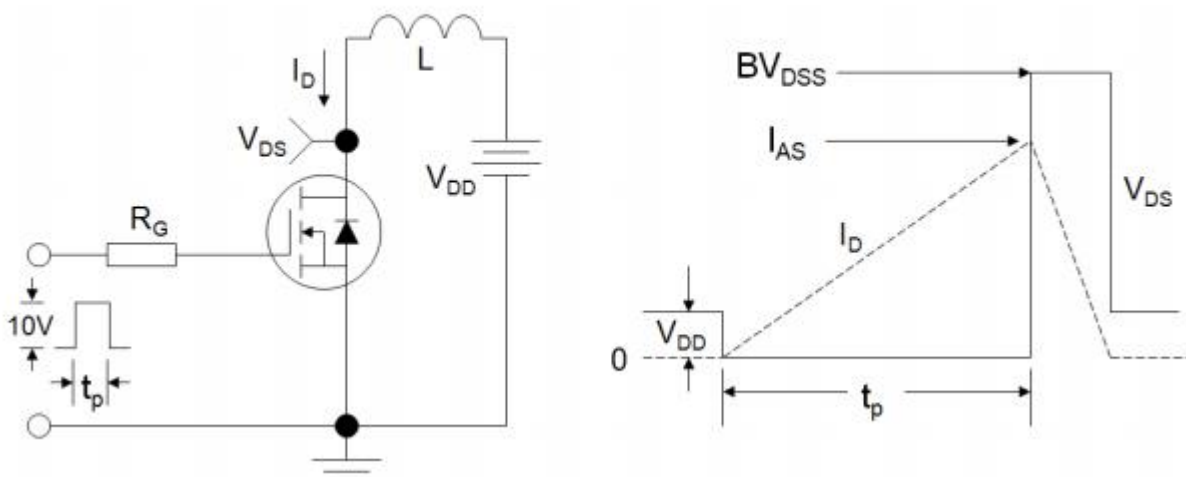
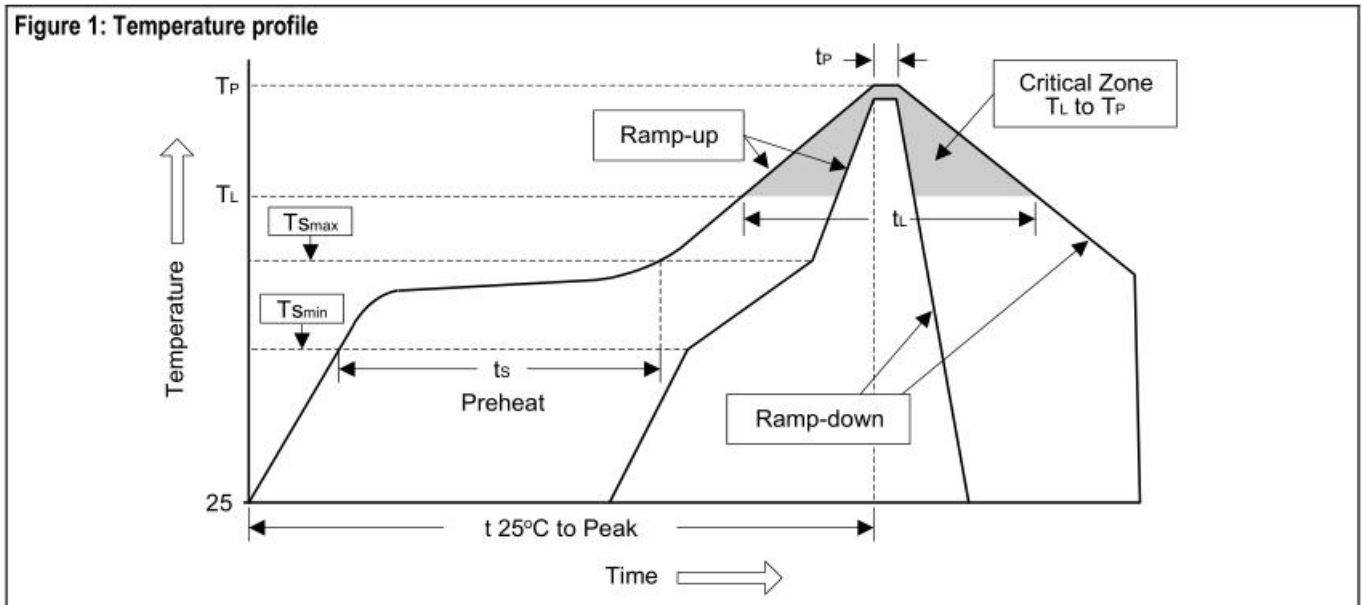


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Soldering Methods for Products

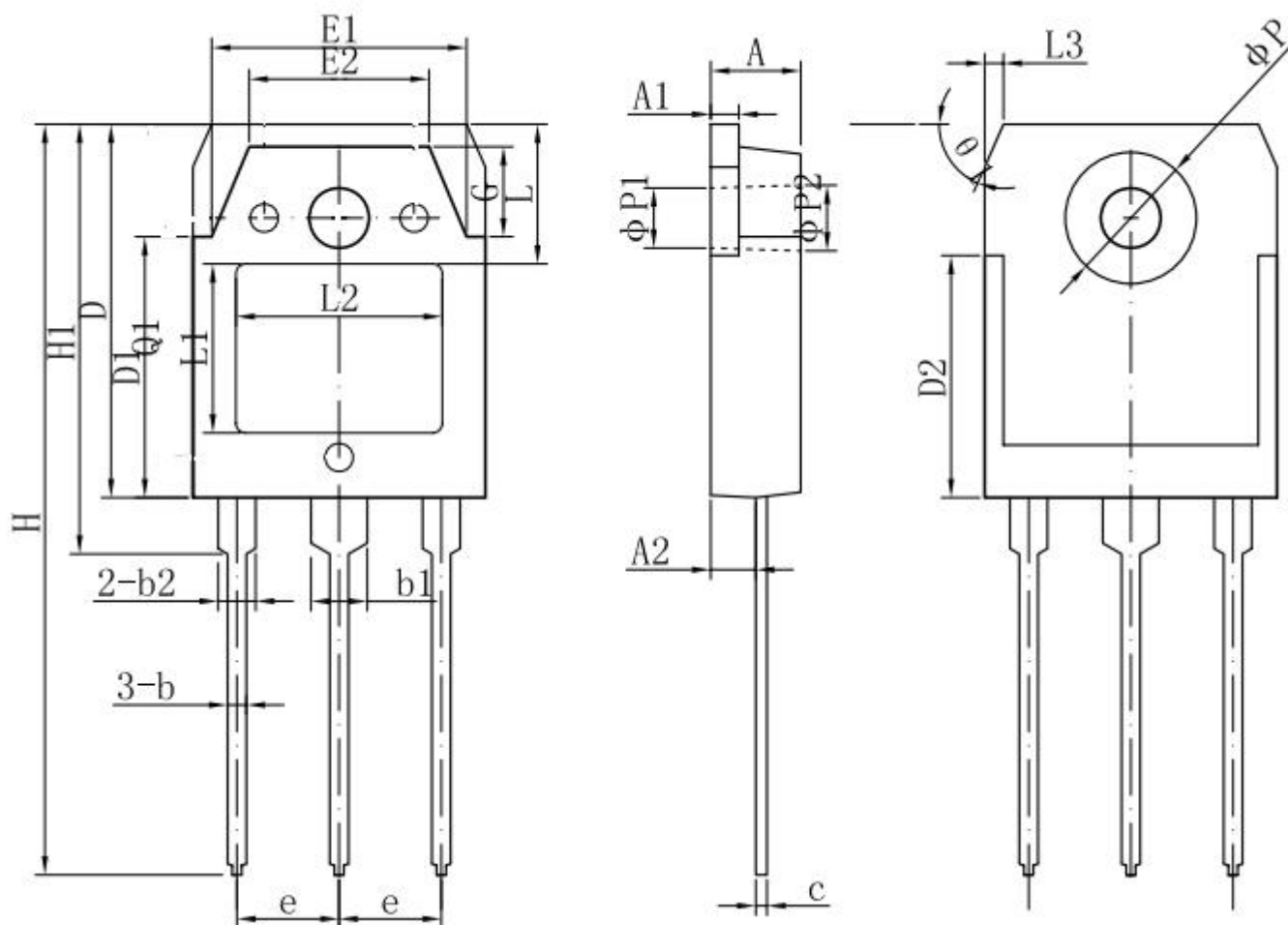
Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate(TL to TP)	<3°C/sec	<3°C/sec
Preheat -Temperature Min(Ts min) -Temperature Max(Ts max) -Time(min to max)(ts)	- 100°C 150°C 60 to 120 sec	- 150°C 200°C 60 to 180 sec
Ts max to TL - ramp-up rate	<3°C/sec	<3°C/sec
Time maintained above: -Temperature(TL) -Time(TL)	183°C 60 to 150 sec	217°C 60 to 150 sec
Peak Temperature(TP)	240°C+0/-5°C	250°C+0/-5°C
Time within 5°C of actual Peak Temperature	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25 °C to Peak Temperature	<6 minutes	<8 minutes



- Note :**
- 1.Storage environment: Temperature=10°C to 35@Humidity=45%±15%
 - 2.Reflow soldering of surface-mount devices
 - 3.Flow(wave) soldering(solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices	245°C±5°C	5sec±1sec
Pb-free devices	250°C+0/-5°C	5sec±1sec

Package Outline



unit: mm					
Symbol	Min	Max	Symbol	Min	Max
A	4.60	5.00	E1	13.6Typ.	
A1	1.40	1.60	E2	9.6Typ.	
A2	2.30	2.50	e	5.45Typ.	
b	0.80	1.20	G	4.8Typ.	
b1	2.90	3.25	H	39.5	40.5
b2	1.90	2.25	H1	22.9Typ.	
C	0.50	0.75	L	7.4Typ.	
D	19.7	20.1	L1	9.0Typ.	
D1	13.9Typ.		L2	11.0Typ.	
D2	12.9REF		L3	1.00REF.	

■ Important Notice

Si-Trend reserves the right to change all product 、 product specifications and data without prior notice ; Our customer Please confirm to place an order confirmation before make the integrity of information complete and up-to-date ◦

Any semiconductor under specific conditions are possible to certain failure or malfunction rate ; Customers are responsible in the use of Si-Trend products to system design and manufacturing in compliance with safety standards and adopting safety measures , To avoid the potential risk of failure may cause the personal safety and property loss ◦

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■ Modify record

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20160215	A.0	original	7